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Team Nexperia



PBSS4160U

60 V, 1 A NPN low V_{CEsat} (BISS) transistor Rev. 03 — 11 December 2009

Product data sheet

1. **Product profile**

1.1 General description

NPN low V_{CEsat} Breakthrough In Small Signal (BISS) transistor in a SOT323 (SC-70) Surface Mounted Device (SMD) plastic package.

PNP complement: PBSS5160U.

1.2 Features

- Low collector-emitter saturation voltage V_{CEsat}
- High collector current capability: I_C and I_{CM}
- High collector current gain (h_{FE}) at high I_C
- High efficiency due to less heat generation
- Smaller required Printed-Circuit Board (PCB) area than for conventional transistors

1.3 Applications

- High voltage DC-to-DC conversion
- High voltage MOSFET gate driving
- High voltage motor control
- High voltage power switches (e.g. motors, fans)
- Automotive applications

1.4 Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{CEO}	collector-emitter voltage	open base	-	-	60	V
I _C	collector current (DC)		[1] _	-	1	Α
I _{CM}	peak collector current	single pulse; $t_p \le 1 \text{ ms}$	-	-	2	Α
R _{CEsat}	collector-emitter saturation resistance	$I_C = 1 \text{ A}; I_B = 100 \text{ mA}$	[2] _	230	280	mΩ

^[1] Device mounted on a ceramic PCB, Al₂O₃, standard footprint.

[2] Pulse test: $t_p \le 300 \ \mu s$; $\delta \le 0.02$.



60 V, 1 A NPN low V_{CEsat} (BISS) transistor

2. Pinning information

Table 2. Pinning

	3	
Pin	Description	Simplified outline Symbol
1	base	
2	emitter	3
3	collector	1 - 2
		sym021

3. Ordering information

Table 3. Ordering information

Type number	er Package		
	Name	Description	Version
PBSS4160U	SC-70	plastic surface mounted package; 3 leads	SOT323

4. Marking

Table 4. Marking codes

Type number	Marking code ^[1]
PBSS4160U	52*

- [1] * = -: made in Hong Kong
 - * = p: made in Hong Kong
 - * = t: made in Malaysia
 - * = W: made in China

60 V, 1 A NPN low V_{CEsat} (BISS) transistor

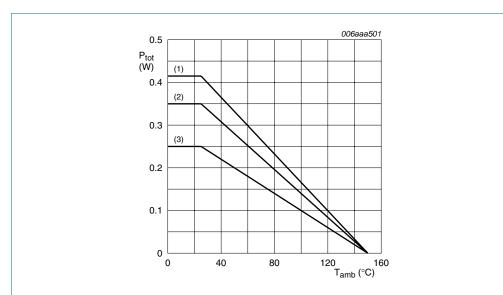
Limiting values 5.

Table 5. **Limiting values**

In accordance with the Absolute Maximum Rating System (IEC 60134).

Parameter	Conditions	Min	Max	Unit
collector-base voltage	open emitter	-	80	V
collector-emitter voltage	open base	-	60	V
emitter-base voltage	open collector	-	5	V
collector current (DC)		[1] -	750	mA
		[2] _	930	mA
		[3]	1	Α
peak collector current	single pulse; $t_p \le 1 \text{ ms}$	-	2	Α
base current (DC)		-	300	mA
peak base current	single pulse; $t_p \le 1 \text{ ms}$	-	1	Α
total power dissipation	$T_{amb} \le 25 ^{\circ}C$	[1] -	250	mW
		[2] _	350	mW
		[3]	415	mW
junction temperature		-	150	°C
ambient temperature		-65	+150	°C
storage temperature		-65	+150	°C
	collector-base voltage collector-emitter voltage emitter-base voltage collector current (DC) peak collector current base current (DC) peak base current total power dissipation junction temperature ambient temperature	$ \begin{array}{llllllllllllllllllllllllllllllllllll$	$ \begin{array}{cccccccccccccccccccccccccccccccccccc$	$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$

- Device mounted on an FR4 PCB, single-sided copper, tin-plated and standard footprint.
- Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for collector 1 cm².
- Device mounted on a ceramic PCB, Al₂O₃, standard footprint.



- (1) Ceramic PCB, Al₂O₃, standard footprint
- (2) FR4 PCB, mounting pad for collector 1 cm²
- (3) FR4 PCB, standard footprint

Fig 1. **Power derating curves**

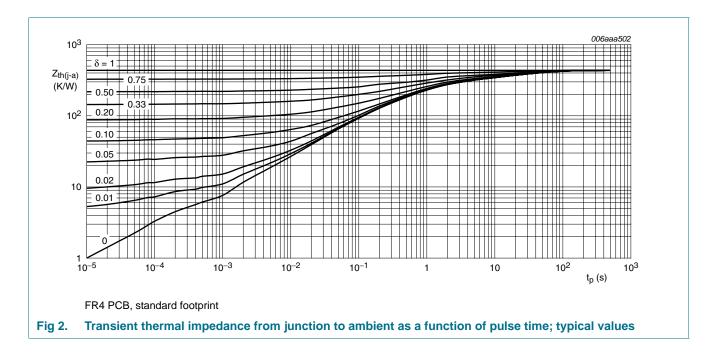
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Thermal characteristics 6.

Table 6. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-a)}$	thermal resistance from junction to ambient	in free air	<u>[1]</u> -	-	500	K/W
			[2] _	-	357	K/W
			[3]	-	301	K/W
$R_{th(j-sp)}$	thermal resistance from junction to solder point		-	-	150	K/W

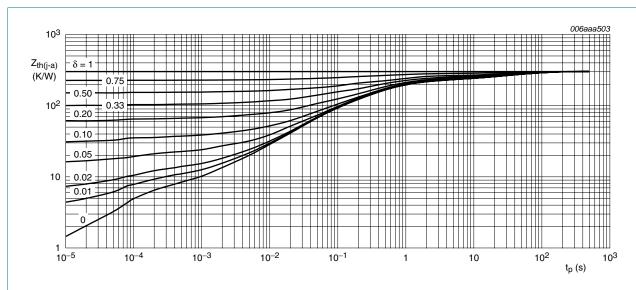
- Device mounted on an FR4 PCB, single-sided copper, tin-plated and standard footprint.
- Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for collector 1 cm².
- Device mounted on a ceramic PCB, Al₂O₃, standard footprint.



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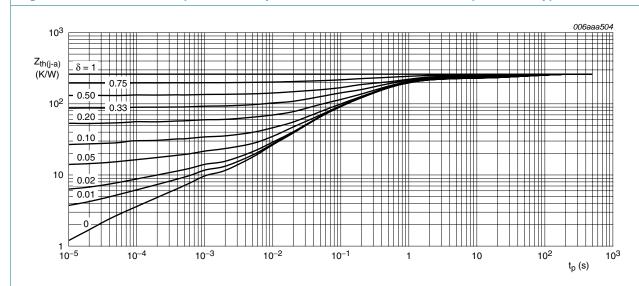
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FR4 PCB, mounting pad for collector 1 cm²

Fig 3. Transient thermal impedance from junction to ambient as a function of pulse time; typical values



Ceramic PCB, Al₂O₃, standard footprint

Fig 4. Transient thermal impedance from junction to ambient as a function of pulse time; typical values

60 V, 1 A NPN low V_{CEsat} (BISS) transistor

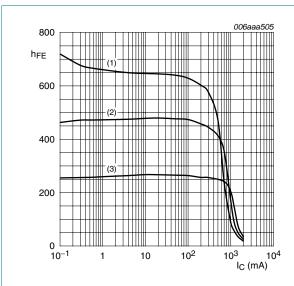
7. Characteristics

Table 7. Characteristics

 $T_{amb} = 25$ °C unless otherwise specified.

0		0 1141		-	24	11.10
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
I_{CBO}	collector-base cut-off	$V_{CB} = 60 \text{ V}; I_{E} = 0 \text{ A}$	-	-	100	nA
	current	$V_{CB} = 60 \text{ V}; I_E = 0 \text{ A};$ $T_j = 150 \text{ °C}$	-	-	50	μА
I _{CES}	collector-emitter cut-off current	$V_{CE} = 60 \text{ V}; V_{BE} = 0 \text{ V}$	-	-	100	nA
I _{EBO}	emitter-base cut-off current	$V_{EB} = 5 \text{ V}; I_{C} = 0 \text{ A}$	-	-	100	nA
h _{FE}	DC current gain	$V_{CE} = 5 \text{ V}; I_{C} = 1 \text{ mA}$	250	500	-	
		$V_{CE} = 5 \text{ V}; I_{C} = 500 \text{ mA}$	[1] 200	420	-	
		$V_{CE} = 5 \text{ V}; I_{C} = 1 \text{ A}$	[<u>1</u>] 100	180	-	
V_{CEsat}	collector-emitter saturation voltage	$I_C = 100 \text{ mA}; I_B = 1 \text{ mA}$	-	90	115	mV
		$I_C = 500 \text{ mA};$ $I_B = 50 \text{ mA}$	-	120	150	mV
		$I_C = 1 A$; $I_B = 100 \text{ mA}$	[1] -	230	280	mV
R _{CEsat}	collector-emitter saturation resistance	$I_C = 1 \text{ A}; I_B = 100 \text{ mA}$	[1] -	230	280	mΩ
V_{BEsat}	base-emitter saturation voltage	$I_C = 1 \text{ A}; I_B = 50 \text{ mA}$	[1] -	0.95	1.1	V
V_{BEon}	base-emitter turn-on voltage	$V_{CE} = 5 \text{ V}; I_{C} = 1 \text{ A}$	[1] -	0.85	0.9	V
t _d	delay time	I _C = 0.5 A;	-	11	-	ns
t _r	rise time	¯ I _{Bon} = 25 mA; − I _{Boff} = −25 mA	-	78	-	ns
t _{on}	turn-on time	180# = -20 IIIA	-	90	-	ns
t _s	storage time		-	340	-	ns
t _f	fall time		-	160	-	ns
t _{off}	turn-off time		-	500	-	ns
f _T	transition frequency	$V_{CE} = 10 \text{ V};$ $I_{C} = 50 \text{ mA};$ f = 100 MHz	150	220	-	MHz
C _c	collector capacitance	$V_{CB} = 10 \text{ V};$ $I_E = i_e = 0 \text{ A}; f = 1 \text{ MHz}$	-	5.5	10	pF

^[1] Pulse test: $t_p \le 300~\mu s;~\delta \le 0.02.$



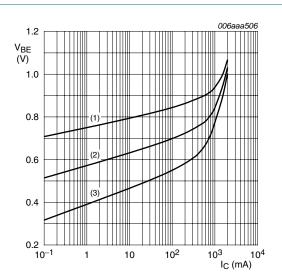
$$V_{CE} = 5 V$$

(1)
$$T_{amb} = 100 \, ^{\circ}C$$

(2)
$$T_{amb} = 25 \, ^{\circ}C$$

(3)
$$T_{amb} = -55 \, ^{\circ}C$$

Fig 5. DC current gain as a function of collector current; typical values



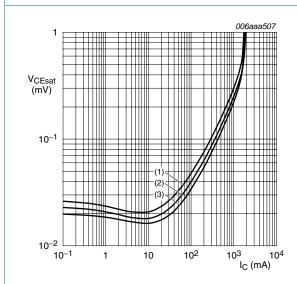
$$V_{CE} = 5 V$$

(1)
$$T_{amb} = -55 \, ^{\circ}C$$

(2)
$$T_{amb} = 25 \, ^{\circ}C$$

(3)
$$T_{amb} = 100 \, ^{\circ}C$$

Fig 6. Base-emitter voltage as a function of collector current; typical values



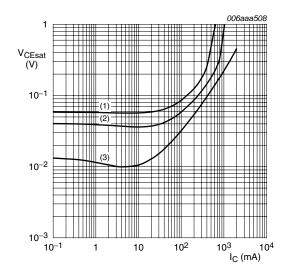
$$I_{\rm C}/I_{\rm B}=20$$

(1)
$$T_{amb} = 100 \, ^{\circ}C$$

(2)
$$T_{amb} = 25 \, ^{\circ}C$$

(3)
$$T_{amb} = -55 \, ^{\circ}C$$

Fig 7. Collector-emitter saturation voltage as a function of collector current; typical values



$$T_{amb} = 25 \, ^{\circ}C$$

(1)
$$I_C/I_B = 100$$

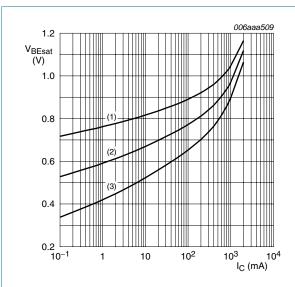
(2)
$$I_C/I_B = 50$$

(3)
$$I_C/I_B = 10$$

Fig 8. Collector-emitter saturation voltage as a function of collector current; typical values

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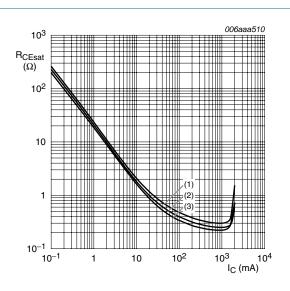
 $I_{\rm C}/I_{\rm B} = 20$

(1) $T_{amb} = -55 \, ^{\circ}C$

(2) $T_{amb} = 25 \, ^{\circ}C$

(3) $T_{amb} = 100 \, ^{\circ}C$

Fig 9. Base-emitter saturation voltage as a function of collector current; typical values



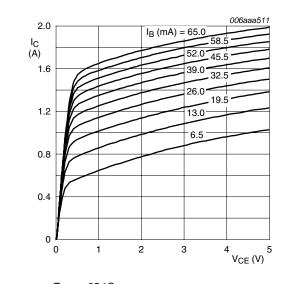
 $I_{\rm C}/I_{\rm B} = 20$

(1) $T_{amb} = 100 \, ^{\circ}C$

(2) $T_{amb} = 25 \, ^{\circ}C$

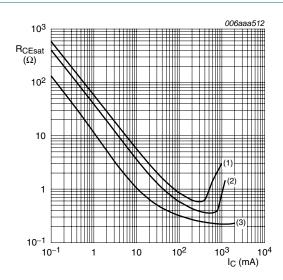
(3) $T_{amb} = -55 \, ^{\circ}C$

Fig 10. Collector-emitter saturation resistance as a function of collector current; typical values



 $T_{amb} = 25 \, ^{\circ}C$

Fig 11. Collector current as a function of collector-emitter voltage; typical values



 $T_{amb} = 25 \, ^{\circ}C$

(1) $I_C/I_B = 100$

(2) $I_C/I_B = 50$

(3) $I_C/I_B = 10$

Fig 12. Collector-emitter saturation resistance as a function of collector current; typical values

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Test information

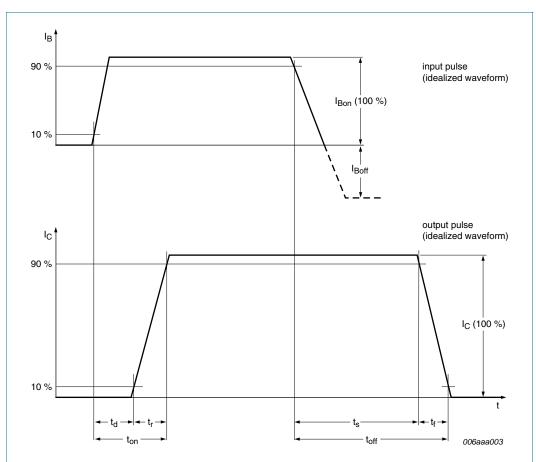
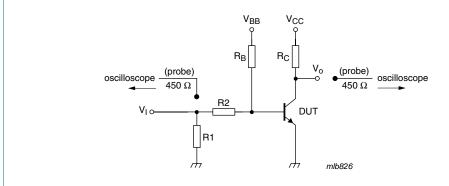


Fig 13. BISS transistor switching time definition

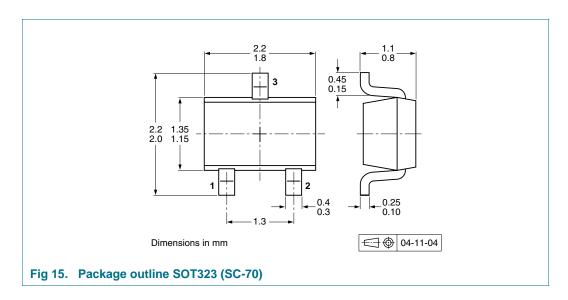


 $\rm I_C$ = 0.5 A; $\rm I_{Bon}$ = 25 mA; $\rm I_{Boff}$ = –25 mA; R1 = open; R2 = 100 $\Omega;$ $\rm R_B$ = 300 $\Omega;$ $\rm R_C$ = 20 Ω

Fig 14. Test circuit for switching times

60 V, 1 A NPN low V_{CEsat} (BISS) transistor

9. Package outline



10. Packing information

Table 8. Packing methods

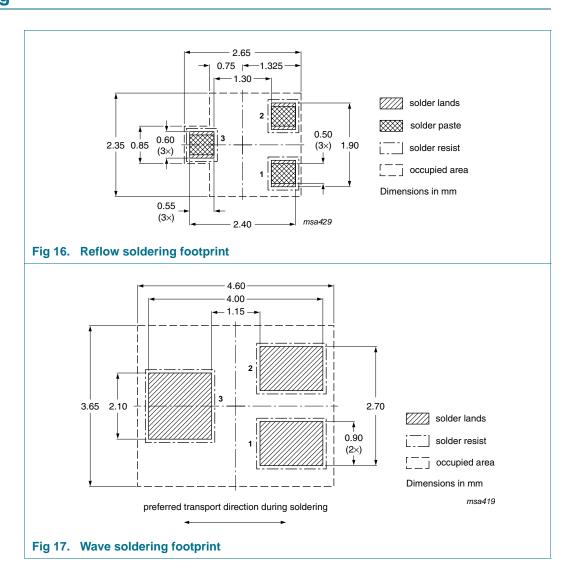
The indicated -xxx are the last three digits of the 12NC ordering code.[1]

Type number	Package	Description		Packing quantity	
				3000	10000
PBSS4160U	SOT323	4 mm pitch, 8 mm tape and reel		-115	-135

[1] For further information and the availability of packing methods, see $\underline{\text{Section 14}}$.

60 V, 1 A NPN low V_{CEsat} (BISS) transistor

11. Soldering



60 V, 1 A NPN low V_{CEsat} (BISS) transistor

12. Revision history

Table 9. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes	
PBSS4160U_3	20091211	Product data sheet	-	PBSS4160U_2	
Modifications:	 This data sheet was changed to reflect the new company name NXP Semiconductorincluding new legal definitions and disclaimers. No changes were made to the tech content. 				
	• Figure 16 "Refle	ow soldering footprint": upd	ated		
	Figure 17 "Wav	e soldering footprint": upda	ted		
PBSS4160U_2	20050719	Product data sheet	-	PBSS4160U_1	
PBSS4160U_1	20040423	Objective data sheet	-	-	

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13. Legal information

13.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
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- 1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions".
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